


<b>Search Notes</b>  	<b>Application/Control No.</b>  10717632	<b>Applicant(s)/Patent Under Reexamination</b>  VERBINSKI ET AL.
	<b>Examiner</b>  Lee, Shun	<b>Art Unit</b>  2884

SEARCHED			
Class	Subclass	Date	Examiner
250	358.1	6/28/2007	/SL/
250	336.08	6/28/2007	/SL/
250	359.1	6/28/2007	/SL/
250	360.1	6/28/2007	/SL/
378	57	6/28/2007	/SL/
378	198	6/28/2007	/SL/
Above	UPDATED.	12/18/2007	/SL/

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	12/18/2007	/SL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner